

November 2014

## **FDMS8570S**

## N-Channel PowerTrench® SyncFET<sup>TM</sup>

**25 V, 60 A, 2.8 m**Ω

#### **Features**

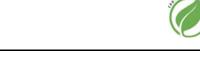
- Max  $r_{DS(on)} = 2.8 \text{ m}\Omega$  at  $V_{GS} = 10 \text{ V}$ ,  $I_D = 24 \text{ A}$
- Max  $r_{DS(on)} = 3.1 \text{ m}\Omega$  at  $V_{GS} = 4.5 \text{ V}$ ,  $I_D = 22 \text{ A}$
- High performance technology for extremely low r<sub>DS(on)</sub>
- SyncFET<sup>TM</sup> Schottky Body Diode
- RoHS Compliant

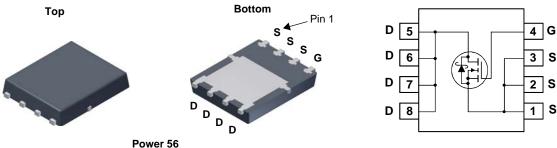
#### **General Description**

This N-Channel SyncFET<sup>TM</sup> is produced using Fairchild Semiconductor's advanced PowerTrench® process. Advancements in both silicon and package technologies have been combined to offer the lowest r<sub>DS(on)</sub> while maintaining excellent switching performance by extremely low Junction-to-Ambient thermal resistance. This device has the added benefit of an efficient monolithic Schottky body diode.

#### **Applications**

- Synchronous Rectifier for DC/DC Converters
- Telecom Secondary Side Rectification
- High End Server/Workstation Vcore Low Side





## **MOSFET Maximum Ratings** T<sub>A</sub> = 25°C unless otherwise noted

Symbol	Parameter	Ratings	Units		
$V_{DS}$	Drain to Source Voltage			25	V
$V_{GS}$	Gate to Source Voltage			12	V
	Drain Current -Continuous (Package limited)	T <sub>C</sub> = 25 °C		60	
$I_D$	-Continuous	T <sub>A</sub> = 25 °C	(Note 1a)	24	Α
	-Pulsed			100	
E <sub>AS</sub>	Single Pulse Avalanche Energy		(Note 3)	45	mJ
В	Power Dissipation	T <sub>C</sub> = 25 °C		48	W
$P_{D}$	Power Dissipation	T <sub>A</sub> = 25 °C	(Note 1a)	2.5	VV
T <sub>J</sub> , T <sub>STG</sub>	Operating and Storage Junction Temperature Range			-55 to +150	°C

#### **Thermal Characteristics**

$R_{\theta JC}$	Thermal Resistance, Junction to Case	T <sub>C</sub> = 25 °C	2.6	°C/W
$R_{\theta JA}$	Thermal Resistance, Junction to Ambient	(Note 1a)	50	C/VV

#### **Package Marking and Ordering Information**

Device Marking	Device	Package	Reel Size	Tape Width	Quantity
10OD	FDMS8570S	Power 56	13"	12 mm	3000 units

## Electrical Characteristics T<sub>J</sub> = 25 °C unless otherwise noted

Symbol	Parameter	Test Conditions	Min	Тур	Max	Units
Off Chara	acteristics					
BV <sub>DSS</sub>	Drain to Source Breakdown Voltage	$I_D = 1 \text{ mA}, V_{GS} = 0 \text{ V}$	25			V
$\frac{\Delta BV_{DSS}}{\Delta T_{J}}$	Breakdown Voltage Temperature Coefficient	I <sub>D</sub> = 10 mA, referenced to 25 °C		23		mV/°C
I <sub>DSS</sub>	Zero Gate Voltage Drain Current	V <sub>DS</sub> = 20 V, V <sub>GS</sub> = 0 V			500	μΑ
I <sub>GSS</sub>	Gate to Source Leakage Current	V <sub>GS</sub> = +12 V/-8 V, V <sub>DS</sub> = 0 V			±100	nA

#### **On Characteristics**

V <sub>GS(th)</sub>	Gate to Source Threshold Voltage	$V_{GS} = V_{DS}$ , $I_D = 1 \text{ mA}$	1.1	1.5	2.2	V
$\frac{\Delta V_{GS(th)}}{\Delta T_J}$	Gate to Source Threshold Voltage Temperature Coefficient	I <sub>D</sub> = 10 mA, referenced to 25 °C		-3		mV/°C
r <sub>DS(on)</sub>	Static Drain to Source On Resistance	V <sub>GS</sub> = 10 V, I <sub>D</sub> = 24 A		2.1	2.8	mΩ
		$V_{GS} = 4.5 \text{ V}, I_D = 22 \text{ A}$		2.4	3.1	
		V <sub>GS</sub> = 10 V, I <sub>D</sub> = 24 A, T <sub>J</sub> = 125 °C		2.9	3.9	
9 <sub>FS</sub>	Forward Transconductance	V <sub>DS</sub> = 5 V, I <sub>D</sub> = 24 A		215		S

#### **Dynamic Characteristics**

C <sub>iss</sub>	Input Capacitance	V 42.V V 0.V	2825	pF
C <sub>oss</sub>	Output Capacitance	$V_{DS} = 13 \text{ V}, V_{GS} = 0 \text{ V},$ $f = 1 \text{ MHz}$	662	pF
C <sub>rss</sub>	Reverse Transfer Capacitance	1 - 1 101112	94	pF
$R_{\alpha}$	Gate Resistance		0.8	Ω

#### **Switching Characteristics**

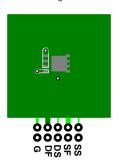
t <sub>d(on)</sub>	Turn-On Delay Time		11	ns
t <sub>r</sub>	Rise Time	V <sub>DD</sub> = 13 V, I <sub>D</sub> = 24 A,	4	ns
t <sub>d(off)</sub>	Turn-Off Delay Time	$V_{GS}$ = 10 V, $R_{GEN}$ = 6 $\Omega$	33	ns
t <sub>f</sub>	Fall Time		3	ns
$Q_g$	Total Gate Charge	V <sub>GS</sub> = 0 V to 10 V	42	nC
$Q_{g}$	Total Gate Charge	$V_{GS} = 0 \text{ V to } 4.5 \text{ V} V_{DD} = 13 \text{ V},$	22	nC
$Q_{gs}$	Gate to Source Gate Charge	I <sub>D</sub> = 24 A	6.4	nC
$Q_{gd}$	Gate to Drain "Miller" Charge		4.4	nC

#### **Drain-Source Diode Characteristics**

V <sub>SD</sub>	Source to Drain Diode Forward Voltage	$V_{GS} = 0 \text{ V}, I_S = 2 \text{ A}$ (Note 2)	0.6	0.8	V
	Source to Drain blode Polward voltage	$V_{GS} = 0 \text{ V}, I_S = 24 \text{ A}$ (Note 2)	0.8	1.2	
t <sub>rr</sub>	Reverse Recovery Time	I <sub>E</sub> = 24 A, di/dt = 300 A/μs	22		ns
$Q_{rr}$	Reverse Recovery Charge	$I_{\rm F} = 24  \text{A},  \text{di/dt} = 300  \text{A/} \mu \text{S}$	19		nC

NOTES:

<sup>1.</sup>  $R_{\theta JA}$  is determined with the device mounted on a FR-4 board using a specified pad of 2 oz copper as shown below.  $R_{\theta JC}$  is guaranteed by design while  $R_{\theta CA}$  is determined by the user's board design.



a) 50 °C/W when mounted on a 1 in<sup>2</sup> pad of 2 oz copper



b) 125 °C/W when mounted on a minimum pad of 2 oz copper.

<sup>2.</sup> Pulse Test: Pulse Width < 300  $\mu$ s, Duty cycle < 2.0%. 3. E<sub>AS</sub> of 45 mJ is based on starting T<sub>J</sub> = 25 °C, L = 0.4 mH, I<sub>AS</sub> = 15 A, V<sub>DD</sub> = 23 V, V<sub>GS</sub> = 10 V. 100% test at L = 0.1 mH, I<sub>AS</sub> = 23.8 A.

## **Typical Characteristics** $T_J = 25$ °C unless otherwise noted

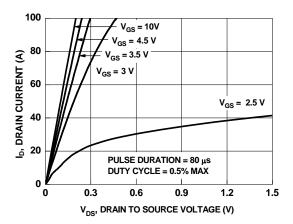


Figure 1. On Region Characteristics

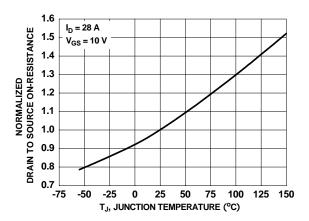


Figure 3. Normalized On Resistance vs Junction Temperature

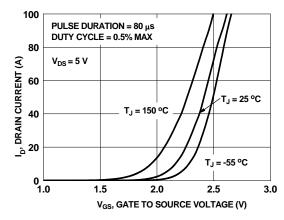


Figure 5. Transfer Characteristics

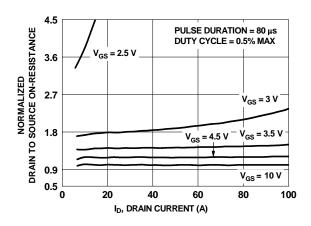


Figure 2. Normalized On-Resistance vs Drain Current and Gate Voltage

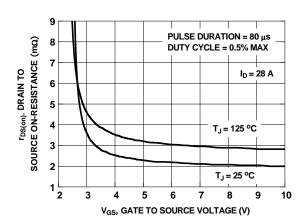


Figure 4. On-Resistance vs Gate to Source Voltage

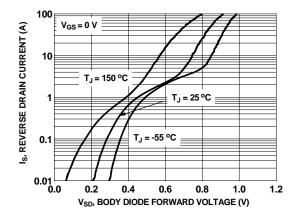


Figure 6. Source to Drain Diode Forward Voltage vs Source Current

## **Typical Characteristics** T<sub>J</sub> = 25 °C unless otherwise noted

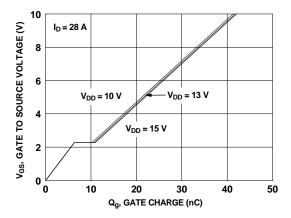


Figure 7. Gate Charge Characteristics

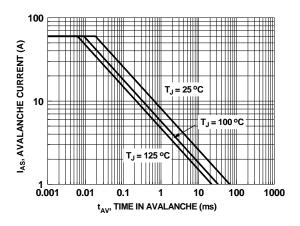


Figure 9. Unclamped Inductive Switching Capability

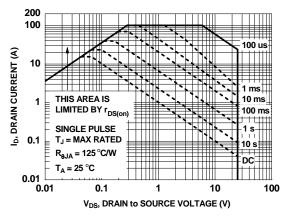


Figure 11. Forward Bias Safe Operating Area

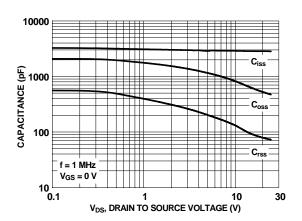


Figure 8. Capacitance vs Drain to Source Voltage

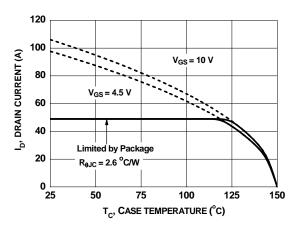


Figure 10. Maximum Continuous Drain Current vs Ambient Temperature

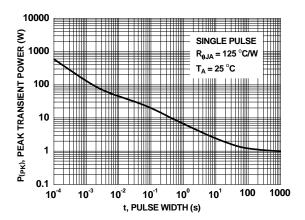


Figure 12. Single Pulse Maximum Power Dissipation

## **Typical Characteristics** T<sub>J</sub> = 25 °C unless otherwise noted

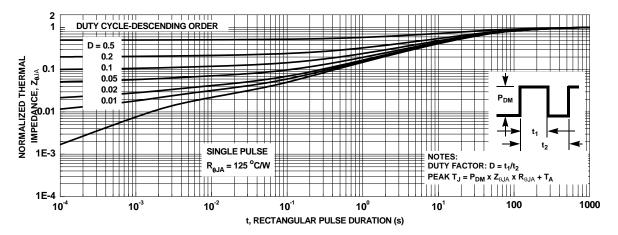


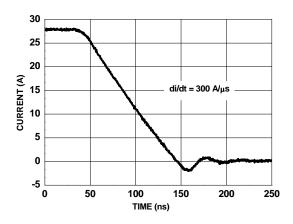
Figure 13. Junction-to-Ambient Transient Thermal Response Curve

## Typical Characteristics (continued)

# SyncFET<sup>TM</sup> Schottky body diode Characteristics

Fairchild's SyncFET<sup>TM</sup> process embeds a Schottky diode in parallel with PowerTrench MOSFET. This diode exhibits similar characteristics to a discrete external Schottky diode in parallel with a MOSFET. Figure 14 shows the reverse recovery characteristic of the FDMS8570S.

Schottky barrier diodes exhibit significant leakage at high temperature and high reverse voltage. This will increase the power in the device.



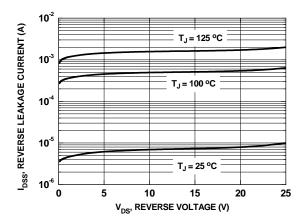
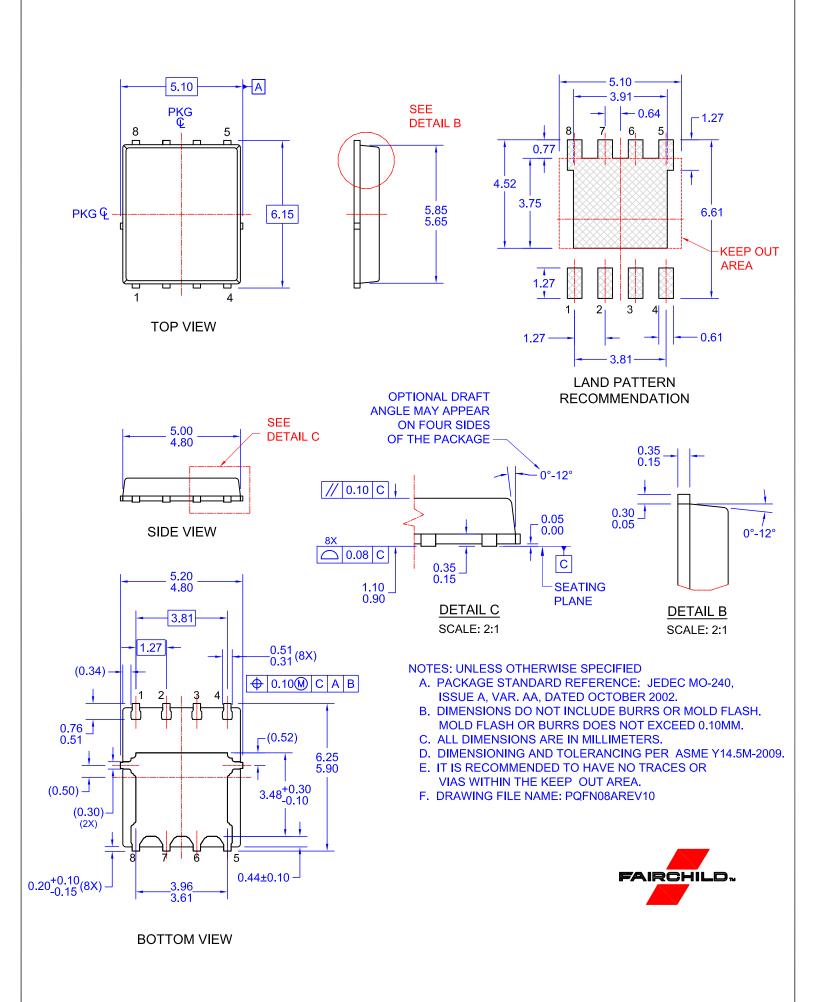


Figure 14. FDMS8570S SyncFET<sup>TM</sup> body diode reverse recovery characteristic

Figure 15. SyncFET<sup>TM</sup> body diode reverse leakage versus drain-source voltage



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